## Issue Classification



CLASS

 ORIGINAL

Application/Control	No.

STIDGE ASS

Examiner GERMAN VIANA DI PRISCO Applicant(s)/Patent Under Reexamination

NON CLAIMED

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INTERNATIONAL CLASSIFICATION

Art Unit 

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/GERMAN VIANA DI PRISCO/ Examiner, Art Unit 2617	03/08/2010	Total Claims Allowed:				
(Assistant Examiner)	(Date)					
/Rafael Pérez-Gutiérrez/ Supervisory Patent Examiner, Art Unit 2617	03/24/2010	O.G. Print Claim(s)	O.G. Print Figure			
(Primary Examiner)	(Date)	1	7			